



# TestConX™

## Archive

DoubleTree by Hilton  
Mesa, Arizona  
March 3-6, 2024

# Effective back-drilling strategies for 200G+ PAM4 Designs

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# TestConX 2024

## Contents

- Need for Back-Drills on Highspeed Designs
- Scope and Objective of the Test
- Test Definition and Measurement Setup
- Simulation Results and Measurement Correlation
- Test Vehicle Validation using Cross section
- Summary and Conclusion



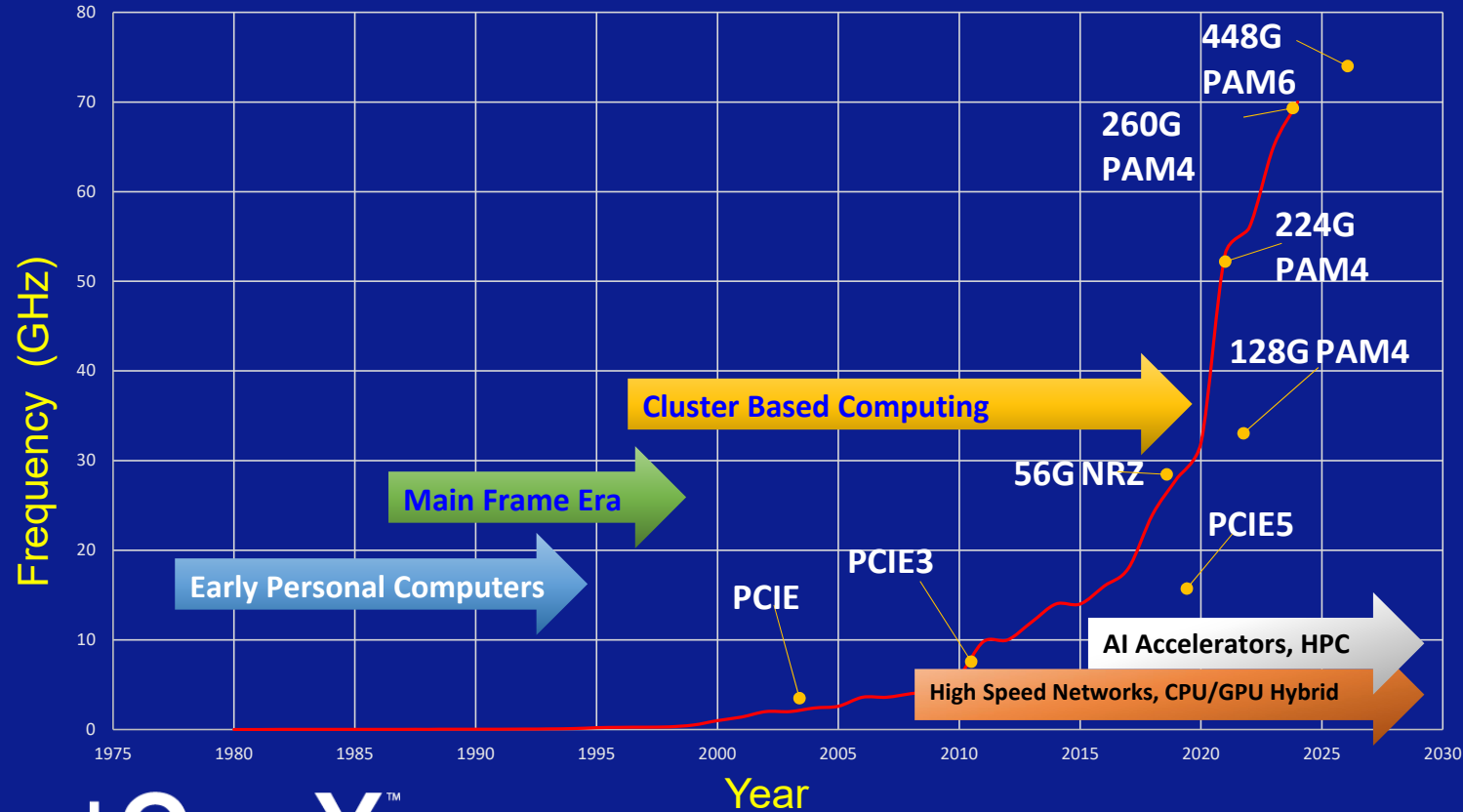
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2



## The Era of High-Performance Compute

PCB Transmission line Data-rate

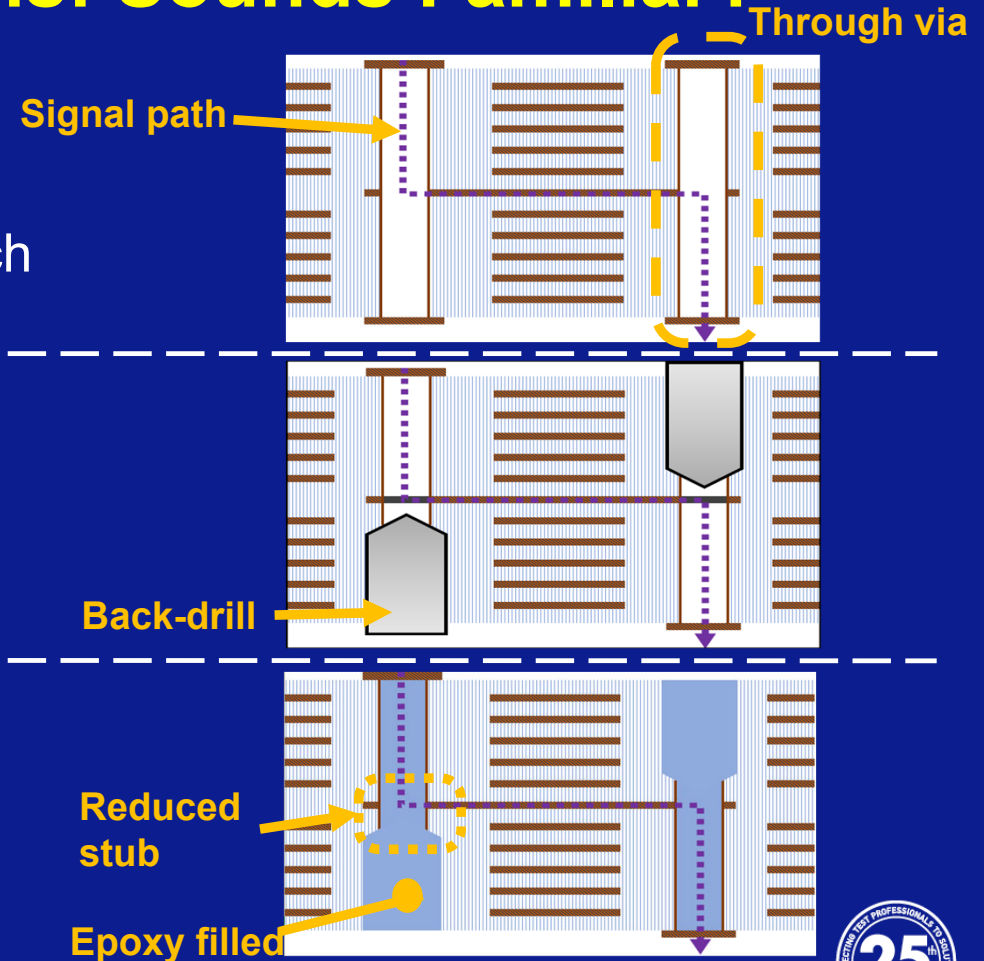


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## Back-Drill in HS Designs: Sounds Familiar?

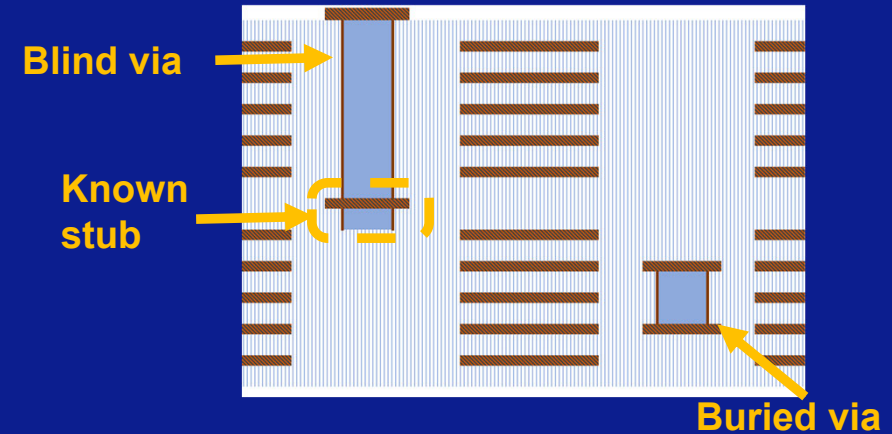
- Signal path has stubs → Causes reflections due to impedance mismatch
- Vias are back-drilled → reduced stub
- Backdrill hole can be filled with non-conductive epoxy



## Traditional Via Strategies for HS Lines

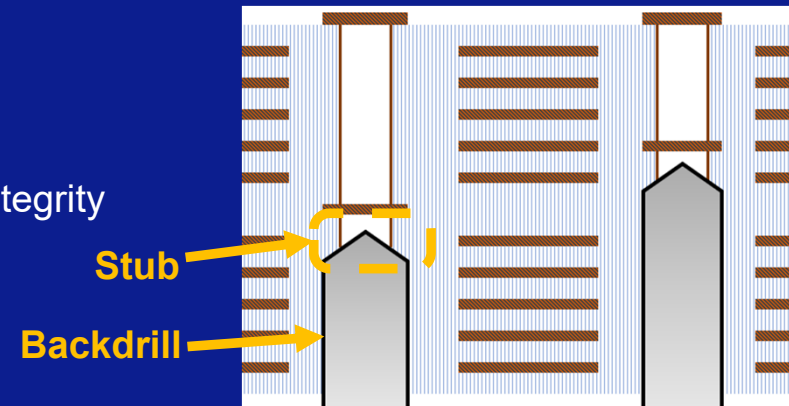
### Blind/Buried vias

- Pros:
  - Known minimum stub
  - Reduces via density for better power delivery
- Cons:
  - longer lead times
  - high cost
  - Not suitable for high channel count



### Through-vias with back-drills

- Pros:
  - Shorter lead times
  - Good cost-effective solution to support signal integrity
  - Can be used in conjunction with blind vias
- Cons:
  - Stub variation impacts signal integrity



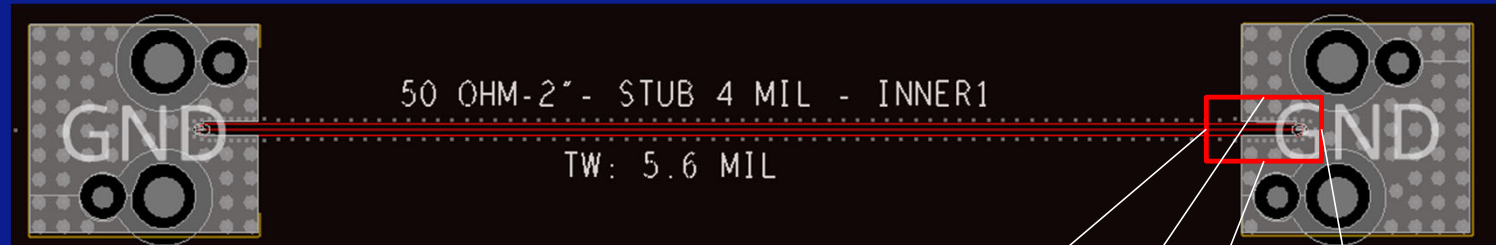
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5

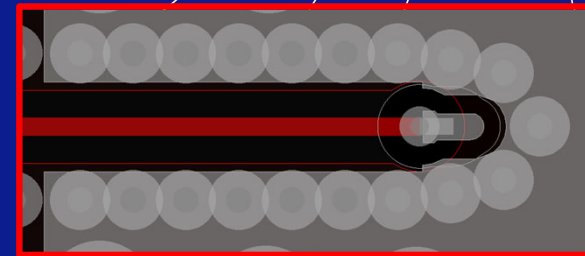


## Test Vehicle Design

### Measurement Structures



- 3 structures per routing layer
  - 12 mils stub
  - 8 mils stub
  - 4 mils stub
- Repeatability: Tested 2x boards



## Engineering Evaluation for Stub Analysis

Qs: What stub length is acceptable for my design?

- Test Vehicle Design Considerations:
  - Board Material : Meteorwave4000
  - Trace Impedance: +/- 5%
  - Stack-up:
    - Board thickness: 188mils [4.77 mm]
      - 32 Layers
      - VLP Copper [Ra 4.5 microns]
  - Other Consideration:
    - Strip-line features: 2" long x 0.0056" wide
    - Design constraint: Compression mount connectors, 50 Ohms transmission lines and vias



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7



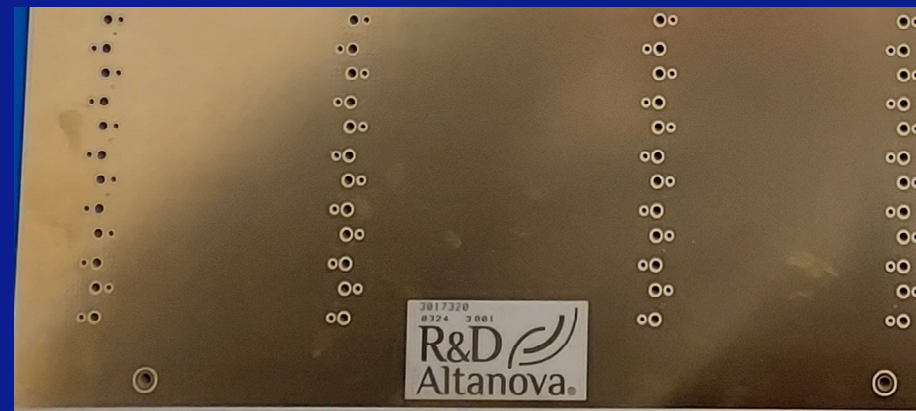


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## Validation Setup

### Setup

- Anritsu 70GHz Vector Network Analyzer [VNA]
- Calibrated up to 1.85mm VNA cables
- Connector P/N: 08K80F-40ML5 [1.85mm]
- Test Vehicle Board



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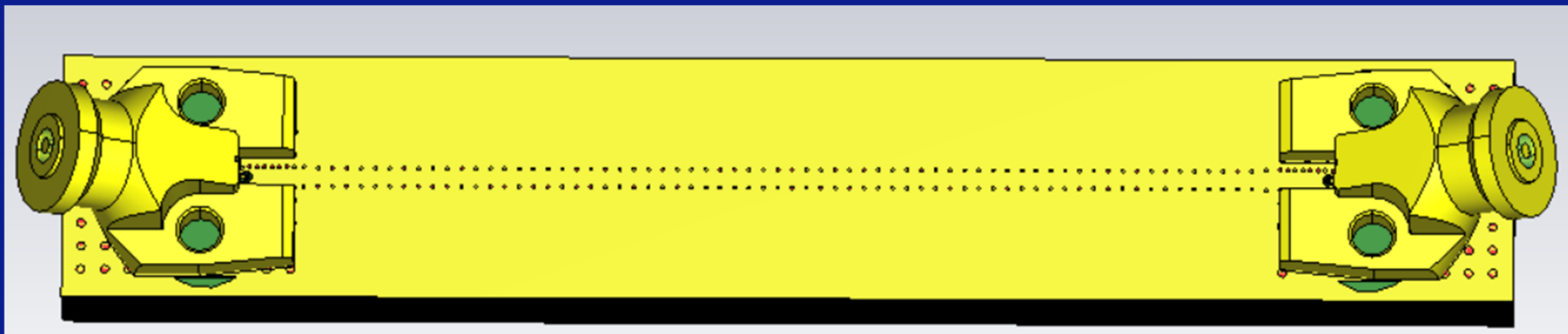
8



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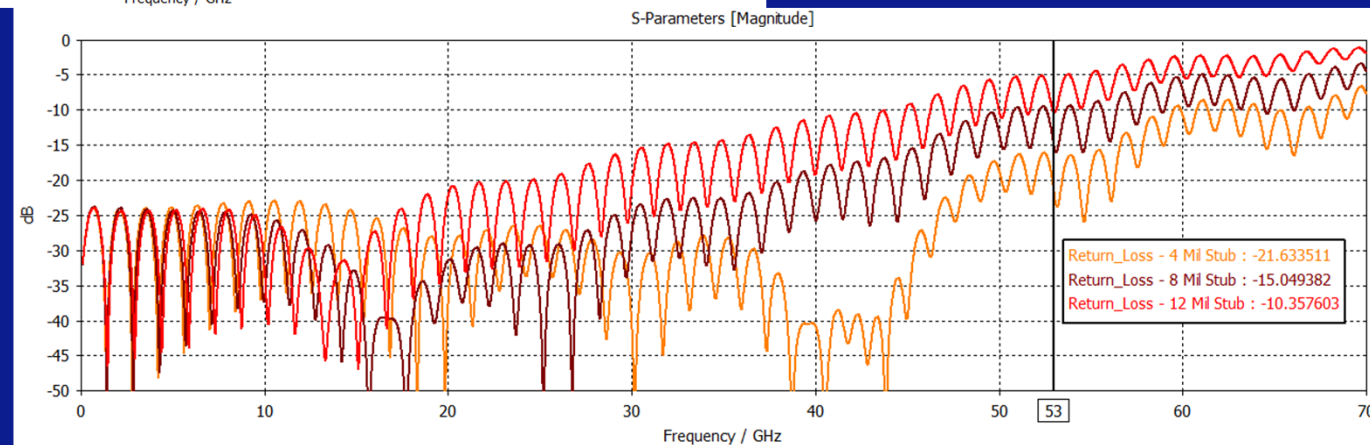
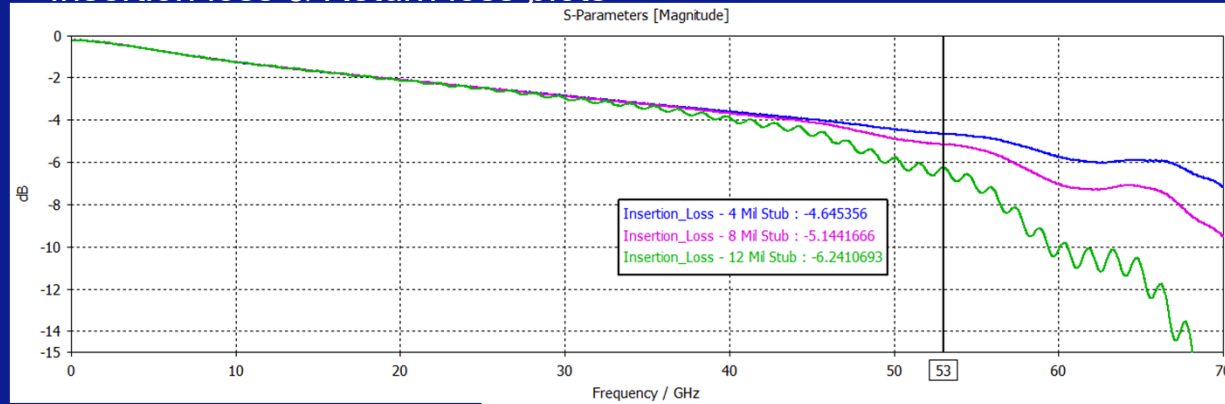
## Modeling Setup

- Modeled with a Full 3D solver [Microwave Studios]
- 4, 8 and 12 mils stub up to 70GHz sweep
- Invisible Vias!
- Copper roughness accounted



## Simulation Results

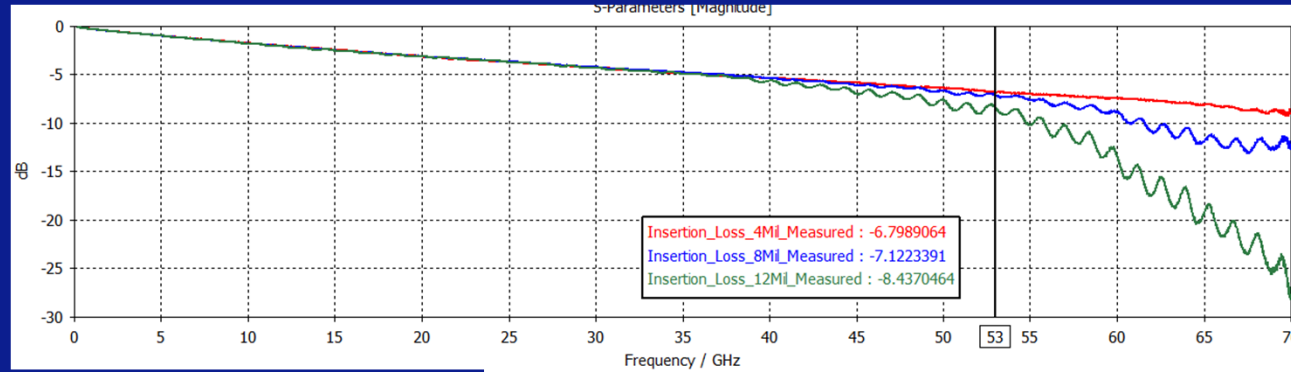
Insertion loss & Return loss plots



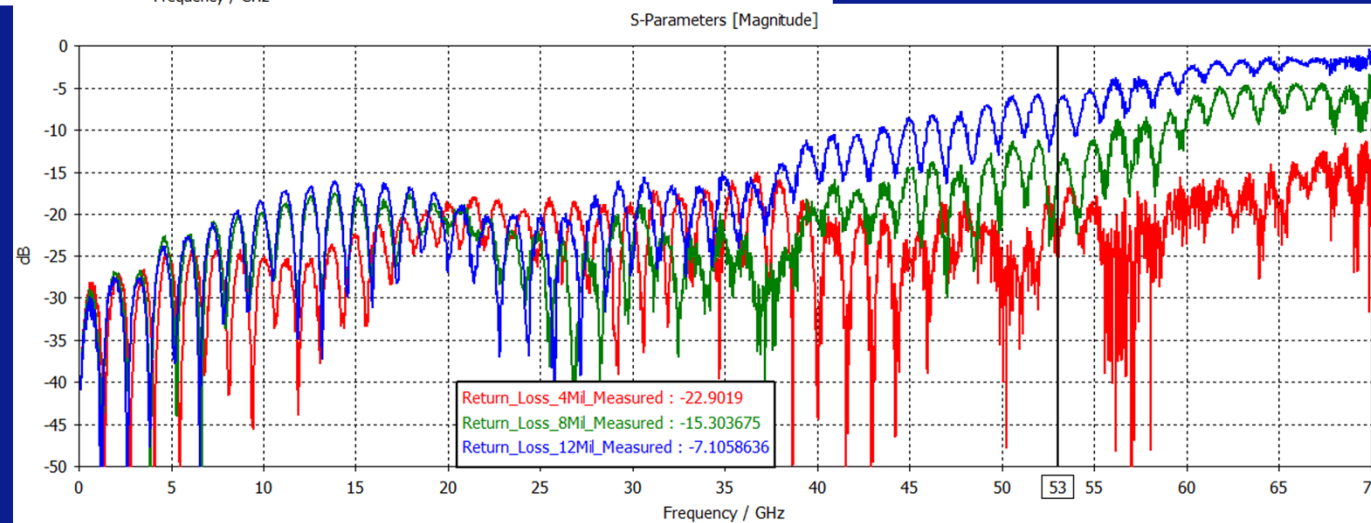
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## Measurements



## Insertion & Return Loss



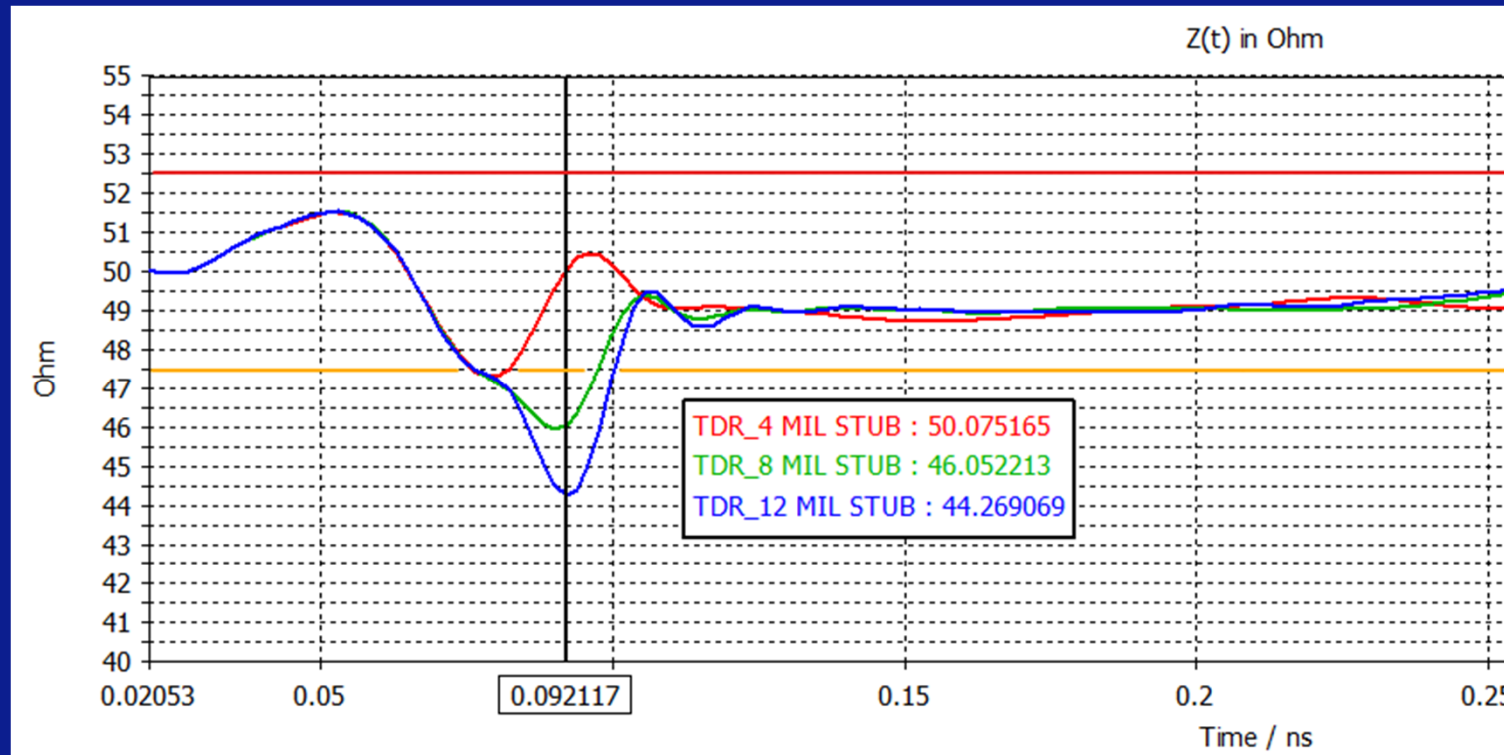
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## Measurements

### TDR

Clear Impedance variation is observed when looking at the TDR



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12

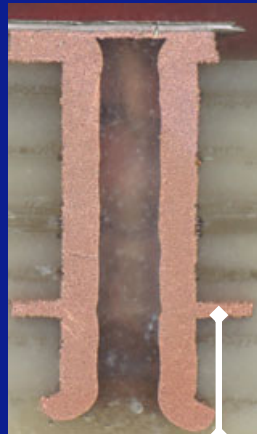


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## Back-Drill Validation

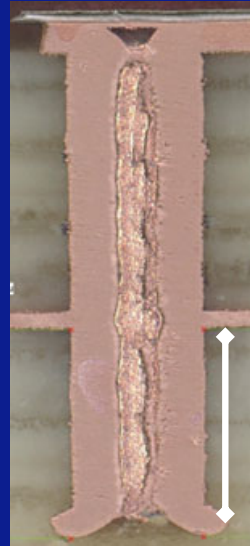
- Boards were cross-sectioned to validate stub length. Measured structures are within manufacturing limits:

4-mil stub



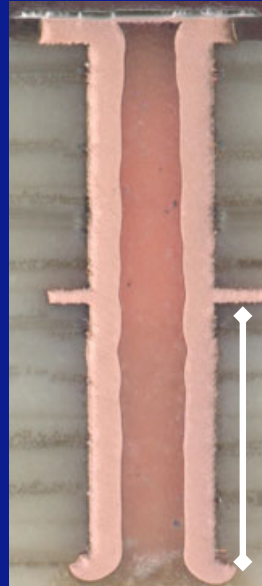
4.56mils

8-mil stub



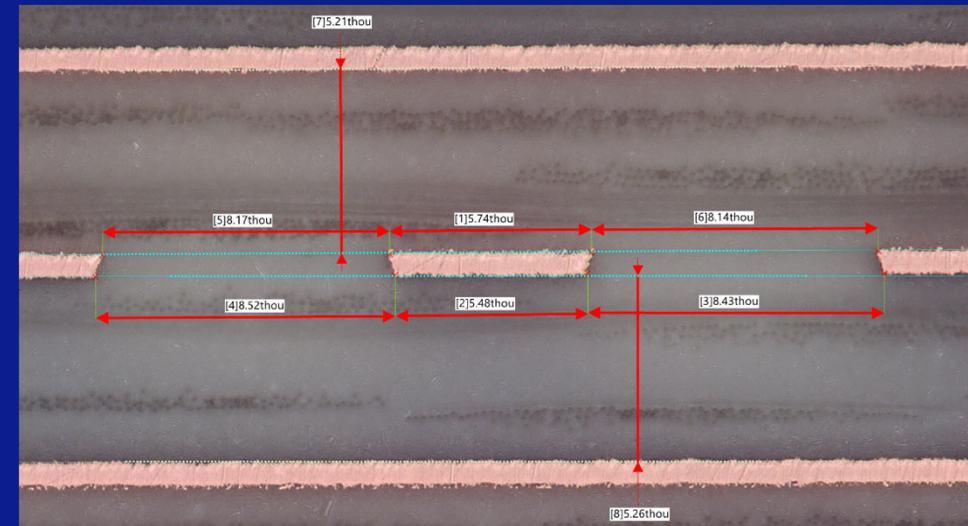
8.36mils

12-mil stub



12.35mils

Trace Cross-Section



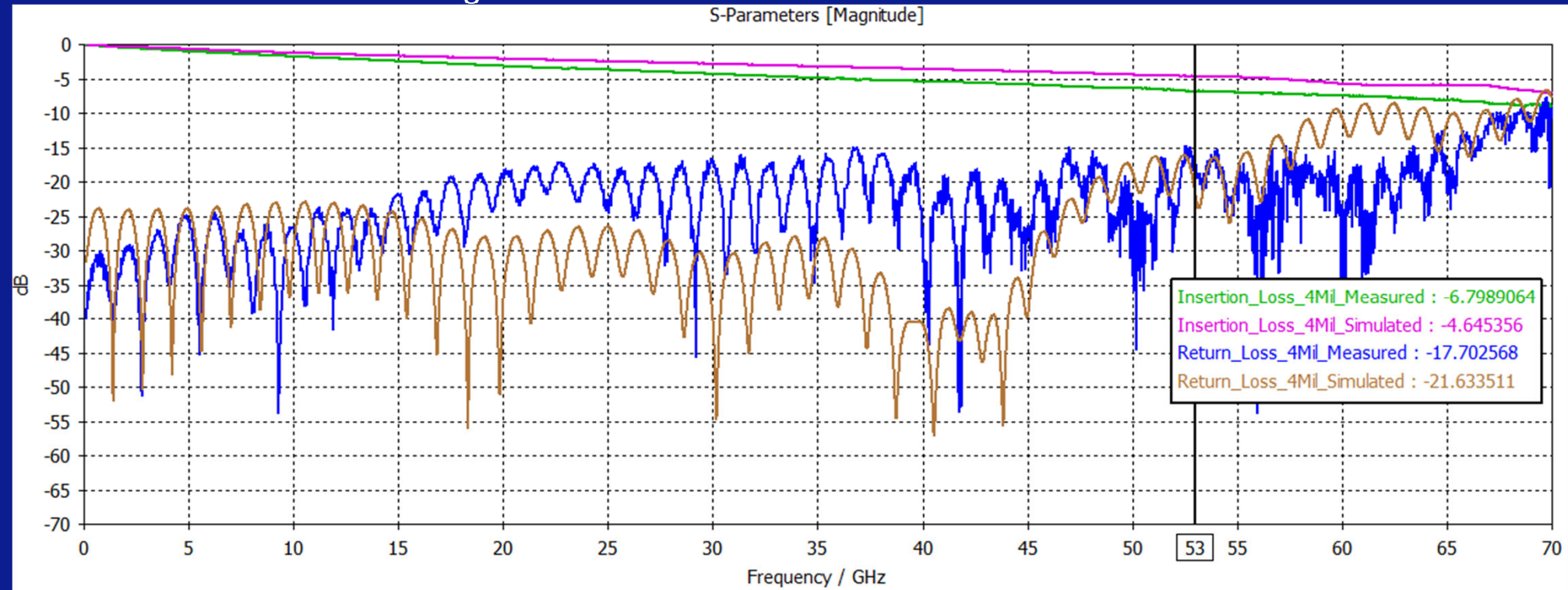
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13

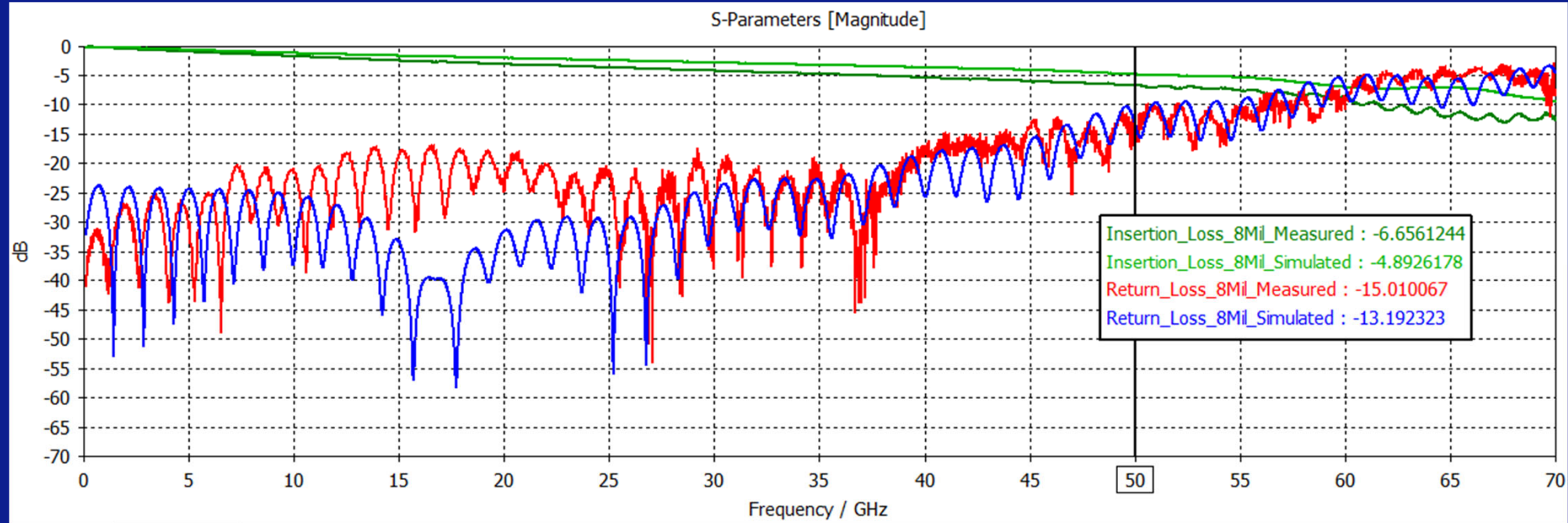


## Measurement Correlation [4 Mil Stub]

- Measurements shows good correlation with simulated data

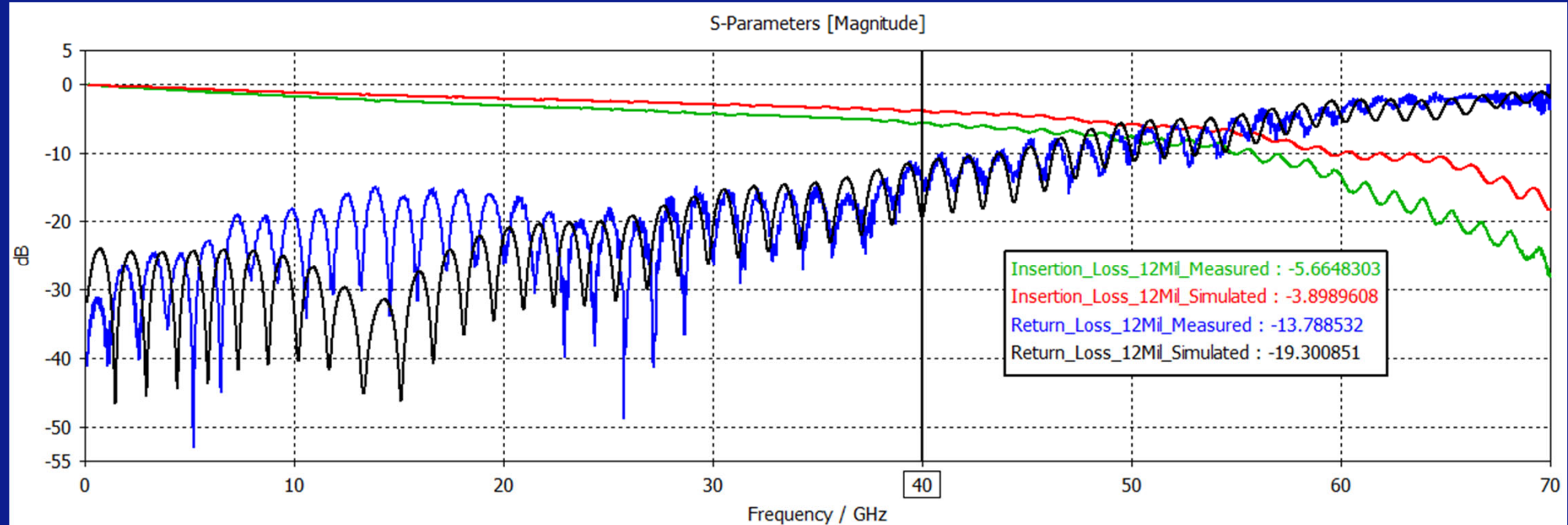


## Measurement Correlation [8 Mil Stub]





## Measurement Correlation [12 Mil Stub]

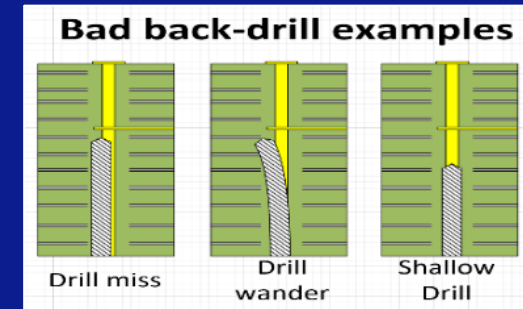
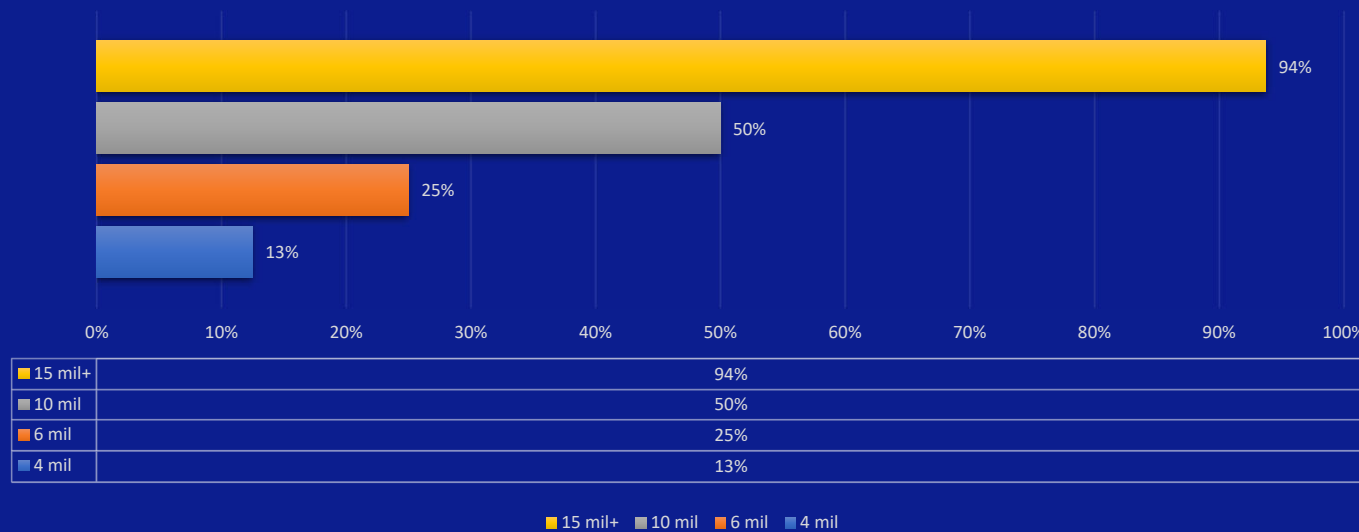


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## Capability Matrix for Advance Back-Drilling

- Estimated market breakdown for Advance ATE FAB back-drilling capability

Back-Drill Capability for Advance ATE FAB Shops



- 4 mil back-drills is critical for 200G+ PAM4 speeds
- Make sure your board vendor has 4 mil back-drill technology



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## Summary and Results

- Back-drills; unlike growing perception is still highly effecting technique for stub removal
- With proper back-drill stub control, 70+ GHz performance can be achieved on PCBs
- With manufacturing tolerances accounted, conservatively; 12 mil or better Back-drills can be used for up to 35 GHz design and 8 mils or better up to 50GHz. For 50GHz+\_Design a premium back-drill under 6 mil is advised.
- Make sure to account for PCB manufacturing tolerances when selecting back-drills. Manufacturing tolerance can account for +/-5% to +/-10%
- Other critical parameters as material selection, impedance control, via optimization, etch control, plating features etc. are equally important considerations

Speed/Modulation	Nyquist	PCB Material	Stub (Simulations)	PCB Impedance Tolerance [Max]
28Gbps NRZ / PAM2	14GHz	METWAVE2K	12 mil	+/-10%
56Gbps PAM4		METWAVE2K	12 mil	+/-10%
PCIE Gen5	16GHz	METWAVE2K	12 mil	+/-10%
56Gbps NRZ / PAM2	28GHz	METWAVE4K	10 mil	+/-5%
112Gb PAM4		METWAVE4K	10 mil	+/-5%
212G PAM4	53GHz	MW4K / MW8K/TACHYON 100G	6 mil	+/-5%
224G PAM4	56GHz	MW4K / MW8K/TACHYON 100G	6 mil	+/-5%
260G PAM4	65GHz	METWAVE8K/TACHYON 100G	4 mil	+/-5%
280G PAM4	70GHz	METWAVE8K/TACHYON 100G	4 mil	+/-5%



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## Honorable Mentions

### RDA performance validation team:

- Henry Lai
- Jacob Neely

### & RDA Front End Engineering:

- Pravin Alurkar
- Syed Raza Ali Rizvi
- Irfan Khalid



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19



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